

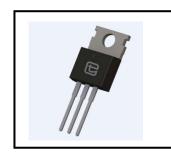
150V N-Channel Trench MOSFET

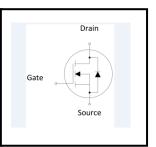
FEATURES

- Trench Power MOSFET Technology
- Low R_{DS(ON)}
- Low Gate Charge
- Optimized For Fast-switching Applications

APPLICATIONS

- Synchronous Rectification in DC/DC and AC/DC Converters
- Isolated DC/DC Converters in Telecom and Industrial







Device Marking and Package Information			
Device	Package	Marking	
TMP17N15A	TO-220	17N15A	

Absolute Maximum Ratings $T_C = 25^{\circ}C$, unless otherwise noted				
Parameter		Symbol	Value	Unit
Drain-Source Voltage (V _{GS} = 0V)		V _{DSS}	150	V
Ossatinosco Desir Ossano	$T_{\rm C} = 25^{\rm o}{\rm C}$		17	А
Continuous Drain Current	$T_{\rm C} = 100^{\rm o}{\rm C}$	l _D	12.7	
Pulsed Drain Current (note1)		I _{DM}	68	Α
Gate-Source Voltage		V_{GSS}	±20	V
Single Pulse Avalanche Energy (note2)		E _{AS}	10.3	mJ
Avalanche Current		I _{As}	8.3	Α
Power Dissipation (note3)	$T_{\rm C} = 25^{\rm o}{\rm C}$	P _D	78.9	W
	$T_{\rm C} = 100^{\rm o}{\rm C}$		39.5	W
Operating Junction and Storage Temperature Range		T_J,T_stg	-55~+175	°C

Thermal Resistance				
Parameter	Symbol	Value	Unit	
Thermal Resistance, Junction-to-Case	R _{thJC}	1.9	°C/W	
Thermal Resistance, Junction-to-Ambient	R _{thJA}	60	°C/VV	



Specifications $T_J = 25^{\circ}C$, unless otherwise noted						
Parameter	Symbol	Test Conditions		Value	Ι	Unit
			Min.	Тур.	Max.	
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_{D} = 250\mu A$	150			V
Zero Gate Voltage Drain Current	l	$V_{DS} = 150V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	μA
zero date voltage Brain dunent	I _{DSS}	$V_{DS} = 150V, V_{GS} = 0V, T_{J} = 100^{\circ}C$			100	μπ
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 20V$	1		±100	nA
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3	4	5	V
Drain-Source On-Resistance	R _{DS(on)}	$V_{GS} = 10V, I_D = 8.5A$	ŀ	70	85	mΩ
Forward Transconductance	g _{fs}	$V_{DS} = 5V, I_{D} = 8.5A$		16.3		S
Dynamic						
Input Capacitance	C _{iss}	$V_{GS} = 0V$,		1440		pF
Output Capacitance	C _{oss}	$V_{DS} = 75V$,		67		
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		26		
Total Gate Charge	Q_g			25		nC
Gate-Source Charge	Q_{gs}	$V_{DD} = 75V, I_{D} = 17A, V_{GS} = 10V$		9		
Gate-Drain Charge	Q_{gd}	50		7		
Turn-on Delay Time	t _{d(on)}			7		
Turn-on Rise Time	t _r	V _{DD} = 75V, I _D = 17A,		13		ns
Turn-off Delay Time	t _{d(off)}	$Vgs=10V,R_G=2.5\Omega$		12		
Turn-off Fall Time	t _f			8		
Drain-Source Body Diode Characteristics						
Continuous Body Diode Current	I _S	T 0500			17	۸
Pulsed Diode Forward Current	I _{SM}	$T_{\rm C} = 25^{\rm o}{\rm C}$			68	А
Body Diode Voltage	V _{SD}	$T_J = 25^{\circ}\text{C}, I_{SD} = 8.5\text{A}, V_{GS} = 0\text{V}$			1.2	V
Reverse Recovery Time	t _{rr}	I _F = 17A,		65		ns
Reverse Recovery Charge	Q _{rr}	di _F /dt = 100A/μs	-	160		nC

Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. VDD = 50V, RG = 25Ω , Starting TJ = 25° C, L=0.3mH
- 3. The power dissipation PD is based on $TJ(MAX)=175^{\circ}C$, using junction-to-case thermal resistance.

Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted

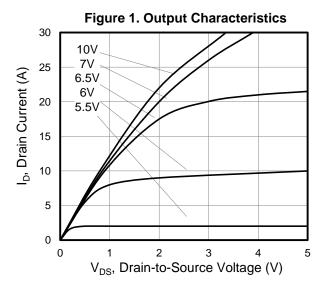
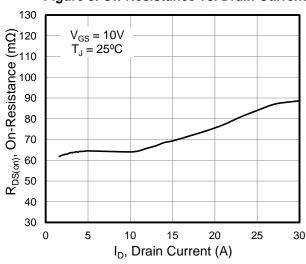


Figure 3. On-Resistance vs. Drain Current



15

Q_q, Total Gate Charge (nC)

25

30

12

0

0

Figure 5. Gate Charge

Figure 2. Transfer Characteristics $V_{DS} = 5V$ $T_{J} = 125^{\circ}C$ $T_{J} = 25^{\circ}C$

0

2

Figure 4. Capacitance

 3 4 5 6 7 V_{GS} , Gate-to-Source Voltage (V)

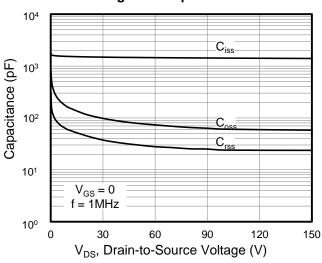
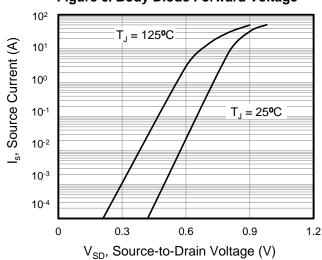


Figure 6. Body Diode Forward Voltage



E

Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted

Figure 7. On-Resistance vs. Junction Temperature

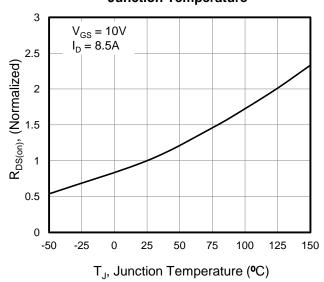


Figure 8. Threshold Voltage vs. Junction Temperature

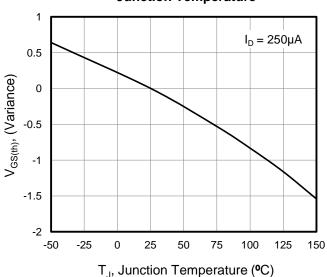


Figure 9. Transient Thermal Impedance

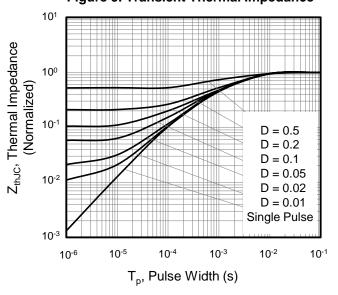


Figure 10. Safe operation area for

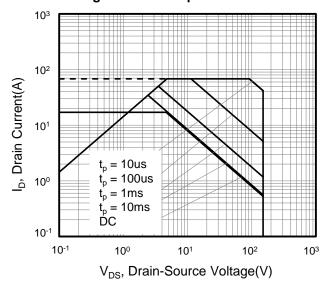




Figure A: Gate Charge Test Circuit and Waveform

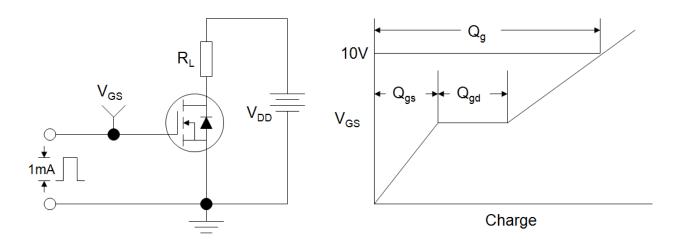


Figure B: Resistive Switching Test Circuit and Waveform

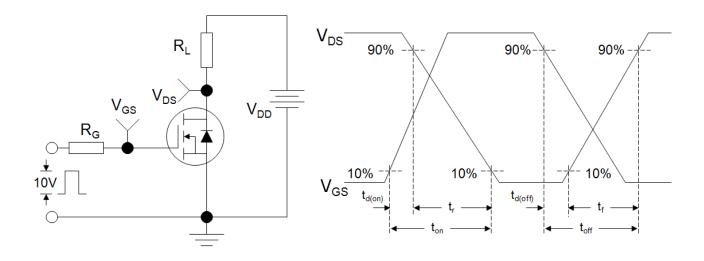
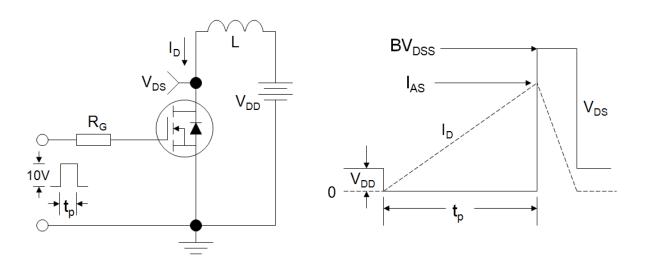
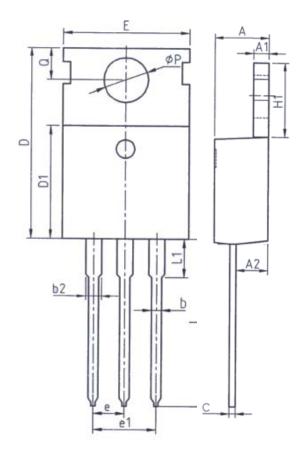


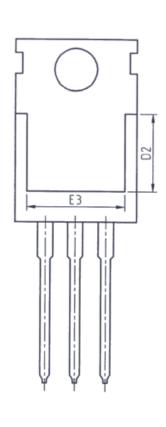
Figure C: Unclamped Inductive Switching Test Circuit and Waveform





TO-220





Unit: mm			
Symbol	Min.	Max.	
Α	4. 37	4. 77	
A1	1. 25	1. 45	
A2	2. 20	2. 60	
b	0. 70	0. 95	
b2	1. 17	1. 47	
С	0. 40	0. 65	
D	15. 10	16. 10	
D1	8. 80	9. 40	
D2	5. 50	_	

Unit: mm			
Symbol	Min.	Max.	
E	9. 70	10. 30	
E3	7. 00	-	
е	2. 54BSC		
e1	5. 08BSC		
H1	6. 25	6. 85	
L	12. 75	13.80	
L1	_	3. 40	
Р	3. 40	3. 80	
Q	2. 60	3. 00	



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